# Η δονητική φασματοσκοπία και οι μηχανικές μετρήσεις στη νανοτεχνολογία

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## From macro to nano



Vandeparre H., et al. PRL, 106, 224301 (2011)





# Various forms of carbon-based nanomaterials



P. Ehrenfreund and B. H. Foing, Science 329, 1159 (2010)



# Mechanical characterization of <u>nanomaterials</u> • MWCNT



Fig. 1. An individual MWCNT mounted between two opposing AFM tips. (A) An SEM image of two AFM tips holding a MWCNT, which is attached at both ends on the AFM silicon tip surface by electron beam deposition of carbonaceous material. The lower AFM tip in the image is on a soft cantilever, the deflection of which is imaged to determine the applied force on the MWCNT. The top AFM tip is on a rigid cantilever that is driven upward to apply tensile load to the MWCNT. (B) High-magnification SEM image of the indicated region in (A), showing the MWCNT between the AFM tips. (C) Higher magnification SEM image showing the attachment of the MWCNT on the top AFM tip. There is an apparent thickening of the MWCNT section on the surface. (D) Close-up SEM image showing the attachment of the MWCNT section is covered by a square-shaped carbonaceous deposit.

#### Force = *kd* ~ 400 – 1340 *nN* Strain = δL/L

Fig. 2 (A) Schematic showing the principle of the tensile-loading experiment. When the top cantilever is driven upward, the lower cantilever is bent upward by a distance d, while the nanotube is stretched from its initial length of L to  $L + \delta L$  because of the force exerted on it by the AFM tips. The force is calculated as kd, where k is the force constant of the lower cantilever. The strain of the nanotube is  $\delta L/L$ . (B) Plot of stress versus strain curves for individual MWCNTs. The E values in Table 1 are as follows: 954 GPa from a linear fit to the upswing part of the curve for nanotube 2 (O); linear fits of the first (470 GPa) and the second (300 GPa) upswings for nanotube 15  $(\Box)$ , and 335 and 274 GPa from linear fits of the whole curve for nanotubes 18 ( $\Delta$ ) and 19 (∇).



#### Fracture strength: 11-63 GPa Strain at break: ~12% Young's Modulus: 274 to 954 GPa

Yu MF, Lourie O, Dyer MJ, Moloni K, Kelly TF, and Ruoff RS, **Strength and breaking mechanism of multiwalled** carbon nanotubes under tensile load, *Science*, 287, 637-640 (2000).



# Mechanical characterization of <u>nanomaterials</u> Graphene





AFM nanoindentation of graphene membrane



Breaking strength ~ 42 N/m Young's modulus ~1.0 Tpa Tensile Strength ~ 130 GPa Lee, et al., Science, 321, (2008), 385-388

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# Force to break a covalent bond in graphene



 It is assumed that the deformation for bond breaking of the C-C bond in graphene is ~ 0.142 nm





Force ~ 65 pN

\*Gross, P. et al. Quantifying how DNA stretches, melts and changes twist under tension. Nature Physics 7, 731–736 (2011).



## Tensile strength and stiffnes of materials – A comparison





# **Raman spectroscopy in Nanomechanics**



## **Raman scattering**

$$P_{\text{Scattered}} = \sigma_{\text{R}} I_{\text{o}}$$

$$\sigma_{\text{R}} = \frac{8\pi\omega_{\text{s}}^{4}}{9\hbarc^{4}} \left| \sum_{j} \left[ \frac{M_{\text{initial},j}M_{j,\text{final}}}{\omega_{\text{initial},j} - \omega_{\text{p}} - i\Gamma_{j}} + \frac{M_{j,\text{initial}}M_{j,\text{final}}}{\omega_{j,\text{final}} - \omega_{\text{p}} - i\Gamma_{j}} \right] \right|^{2}$$

$$P_{\text{Scattered}} \propto \frac{I_{o}}{\lambda^{4}}$$
The Raman effect comprises a very small fraction, about 1 in 10<sup>7</sup>, of the incident photons



• Energy conservation: 
$$\pm \hbar \omega_s = \varepsilon_i - \varepsilon_f$$
  
• Momentum conservation:  $\pm \mathbf{k} = \mathbf{k}_i - \mathbf{k}_f$ 



# **Experimental set-ups**



# Raman spectra of graphitic materials - 2D





# **Raman Spectrum of SWCNT – 1D**





## CF Structure Development and the corresponding Raman spectra of carbon fibres -3D



(Source: A. R. Bunsell, Fibre Reinforcements for Composite Materials, Amsterdam, The Netherlands: Elsevier Science Publishers B.V., 1988, p. 120.)



## **G-band of graphene under Strain in Tension & Compression**











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# Axial Experiments in Graphene (tension & compression combined with Raman measurements)



# **Experimental Set-up for Application of Uniaxial Strain**





#### **Materials & Geometry**

- SU8 photo resist epoxy-based polymer
- PMMA beam substrate (2.9x12.0x70) mm<sup>3</sup>
- *x* = 10.4 mm and *L* = 70 mm





#### Mechanical strain at the top of the beam

$$\varepsilon(x) = \frac{3t\delta}{2L^2} \left(1 - \frac{x}{L}\right)$$

δ: deflection of the beam neutral axis L: span of the beam t : beam thickness

#### **Operating limits:**

- L>>  $10\delta_{max}$
- -1.5% < *ε* < 1.5%





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## G-band vs. Strain (no residual strain)





# Raman 2D-peak splitting in single-layer graphene

**λ=514.5 nm** 





Measurements of the 2D band alone, for excitation energies lower than 2.41 eV (514.5 nm), may lead to errors with regards to the detailed determination state of stress/strain in the specimen.

Frank et al., ACS-Nano, 5, 2321 (2011)





Tsoukleri et al. Small 2009, 5, 2397





Tsoukleri et al. Small 2009, 5, 2397

# **Tensile testsin graphene – Current status**





# Graphene: a powerful stress/ strain sensor

Phonon stress ( $\sigma$ ) or strain ( $\epsilon$ ) sensitivities:

$$\left(\frac{\partial \overline{G}}{\partial \varepsilon}\right)_{T} \sim -27.0 \; (\mathrm{cm}^{-1}\%^{-1}) \implies \left(\frac{\partial \overline{G}}{\partial \sigma}\right)_{T} \sim -2.7 \; (\mathrm{cm}^{-1}\mathrm{GPa}^{-1})$$

For small(??) strains  $\sigma = E \varepsilon$ , E = 1 TPa [Lee et al, Science (2008)]

$$\left(\frac{\partial(2D)}{\partial\varepsilon}\right)_{T} \sim -60.0 \text{ cm}^{-1}(\text{cm}^{-1}\%^{-1}) \longrightarrow \left(\frac{\partial(2D)}{\partial\sigma}\right)_{T} \sim -6.0 \text{ (cm}^{-1}\text{GPa}^{-1})$$

Knowing the wavenumber shift we can resolve the inverse problem i.e. to obtain the values of axial  $\sigma$  and/or  $\varepsilon$  in graphene-based materials through the above relations.

Frank, O. et al. Development of a universal stress sensor for graphene and carbon fibres. Nat Commun 2, 255 (2011).



# Mechanical characterization of single layer graphene



# Axial Experiments in CNT yarns (tension combined with Raman measurements)



# **Draw-Twist process for CNT yarn production**



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# Yarn model geometry (Ideal helical structure)



# Twist (turns/m) of yarns



$$a_s = \arctan\left(\frac{2\pi R}{h}\right) \rightarrow \frac{1}{h} \sim 14786 \text{ m}^{-1}$$

where  $\alpha_s = 26^{\circ}$  and D = 10.5  $\mu$ m were measured by SEM pictures





CNT yarns behave like a viscoelastic Material

- Strain-to-failure increases with strain rate
- CNT yarn strength is 620 MPa and is independent from strain rate
- (friction forces are independent from the rate of the relative
- movement between CNT bundles)



# **CNT yarn fracture surface**



A bundle of MWCNTs located at the yarn centre is clearly unveiled (ii) showing that the bundle is subjected to higher strains when an external tensile load is applied to the yarn. This is consistent with ideal helix yarn models where when an ideal helical structure is under an external tensile load, the fiber strains are largest along the yarn axis and smallest in the outermost layer.



# Stress transfer in CNT yarns – Raman Spectroscopy



- 2D peak position decreases slightly (~4cm<sup>-1</sup>) with strain
- 2D FWHM decreases showing a min value which reflects the decreasing of helix angle and consequently the spread of strain values

These results indicate that the fiber strains are largest along the yarn axis and smallest in the outermost layer.

2D peak position and FWHM as a function of uniaxial tensile strain



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The AFM nano-antenna can locally enhance the electromagnetic field intensity near the tip apex and become a localized "nano-source of light."

P. Dorozhkin et al, Microscopy Today, doi:10.1017/S1551929510000982 (2010)



# Thank you very much for your kind attention !



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